



# CONTENTS

<b>Preface</b> . . . . .	vii
<b>Symbols</b> . . . . .	xi
A. Physical quantities . . . . .	xi
B. Microwave and electronic devices and instruments . . . . .	xiii
C. Abbreviations . . . . .	xviii
<b>1 Introduction</b> . . . . .	1
1.1 General description and classification of comparison methods. . . . .	2
1.2 Application areas . . . . .	4
<b>2 Theory</b> . . . . .	7
2.1 Matrix representation of microwave networks . . . . .	7
2.2 Some important $n$ -ports . . . . .	14
2.3 Definitions and basic relations . . . . .	26
2.4 Idealized comparison networks . . . . .	40
(A) Direct comparison transmission network . . . . .	41
(B) Direct comparison reflection network . . . . .	46
(C) Substitution comparison network . . . . .	51
(D) Reflectometer. . . . .	55
(E) Reflection bridge . . . . .	62
(F) Transmission bridge . . . . .	67
(G) Six-port reflectometer . . . . .	72
(H) Dual reflectometer . . . . .	82
2.5 Sources of measurement error . . . . .	84
<b>3 Measuring set-ups and procedures</b> . . . . .	93
3.1 Reflection coefficient. . . . .	93
3.2 Attenuation . . . . .	123
3.3 Phase shift . . . . .	140
3.4 Scattering coefficients . . . . .	153
3.5 Resonator characteristics. . . . .	163
3.6 Noise . . . . .	195

<b>4 Computer-controlled measurements</b> . . . . .	208
4.1 Description of the computer-controlled measuring system . . .	210
4.2 Programming. . . . .	215
4.3 Some examples of CCM . . . . .	217
4.4 Smart instruments. . . . .	240
<b>5 Miscellaneous applications</b> . . . . .	244
5.1 Characterization of the materials . . . . .	246
5.2 RF characterization of the opto-electronic devices. . . . .	259
5.3 Sensing in industrial processes . . . . .	264
5.4 Plasma diagnostics . . . . .	270
<b>References</b> . . . . .	276
<b>Subject index</b> . . . . .	282